

Notice of References Cited	Application/Control No. 10/630,440	Applicant(s)/Patent Under Reexamination CHIN ET AL.	
	Examiner Beverly M. Flanagan	Art Unit 3739	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2001/0055462	12-2001	Seibel, Eric J.	385/147
	B	US-5,060,632	10-1991	Hibino et al.	600/109
	C	US-4,846,155	07-1989	Kimura, Kenji	600/109
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 1-237613	01-1989	Japan		
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.